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Characterization of Trapped Charges Distribution in Terms of Mirror Plot Curve

Hassan N. Al-Obaidi, Ali S. Mahdi, Imad H. Khaleel

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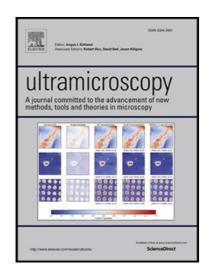
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Highlights

- Potential due to trapped charges in SEM chamber is calculated formally.
- Method of image charges is adopted to define this potential.
- The obtained potential's expression expanded by binomial theorem.
- Resultant potential being formulated in terms multipoles expression.
- The multipoles expression is used to modifying a novel mirror plot formula.
- The derived mirror plot formula is used to detect the real distribution of trapped charges.
- Results revealed that trapped charges may take a various sort of arrangement such as monopole, quadruple and octupole.

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